

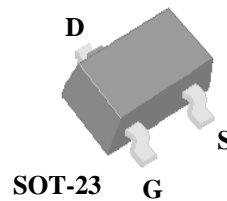
# XP2344GN-HF

Halogen-Free Product

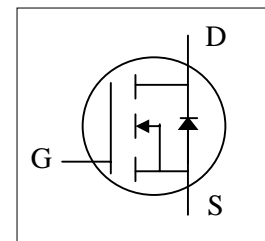


N-CHANNEL ENHANCEMENT MODE  
POWER MOSFET

- ▼ Capable of 1.8V Gate Drive
- ▼ Lower Gate Charge
- ▼ Fast Switching Performance
- ▼ RoHS Compliant & Halogen-Free



$BV_{DSS}$	20V
$R_{DS(ON)}$	22m $\Omega$
$I_D$	6.4A



## Description

XP2344 series are innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The special design SOT-23 package with good thermal performance is widely preferred for all commercial-industrial surface mount applications using infrared reflow technique and suited for voltage conversion or switch applications.

## Absolute Maximum Ratings@ $T_j=25^{\circ}\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	20	V
$V_{GS}$	Gate-Source Voltage	+8	V
$I_D@T_A=25^{\circ}\text{C}$	Drain Current <sup>3</sup> , $V_{GS}$ @ 4.5V	6.4	A
$I_D@T_A=70^{\circ}\text{C}$	Drain Current <sup>3</sup> , $V_{GS}$ @ 4.5V	5.1	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	20	A
$P_D@T_A=25^{\circ}\text{C}$	Total Power Dissipation	1.38	W
$T_{STG}$	Storage Temperature Range	-55 to 150	$^{\circ}\text{C}$
$T_J$	Operating Junction Temperature Range	-55 to 150	$^{\circ}\text{C}$

## Thermal Data

Symbol	Parameter	Value	Unit
Rthj-a	Maximum Thermal Resistance, Junction-ambient <sup>3</sup>	90	$^{\circ}\text{C}/\text{W}$

**Electrical Characteristics @ $T_j=25^{\circ}\text{C}$  (unless otherwise specified)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	20	-	-	V
$R_{DS(ON)}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=4.5V, I_D=6A$	-	-	22	m $\Omega$
		$V_{GS}=2.5V, I_D=4A$	-	-	32	m $\Omega$
		$V_{GS}=1.8V, I_D=2A$	-	-	40	m $\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	0.4	-	1	V
$I_{D(ON)}$	On state drain current	$V_{GS}=4.5V, V_{DS}=5V$	30	-	-	A
$g_{fs}$	Forward Transconductance	$V_{DS}=5V, I_D=6A$	-	27	-	S
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS}=16V, V_{GS}=0V$	-	-	1	$\mu A$
$I_{GSS}$	Gate-Source Leakage	$V_{GS}=\pm 8V, V_{DS}=0V$	-	-	$\pm 10$	$\mu A$
$Q_g$	Total Gate Charge	$I_D=6A$	-	22	35.2	nC
$Q_{gs}$	Gate-Source Charge	$V_{DS}=10V$	-	2	-	nC
$Q_{gd}$	Gate-Drain ("Miller") Charge	$V_{GS}=4.5V$	-	6	-	nC
$t_{d(on)}$	Turn-on Delay Time	$V_{DS}=10V$	-	8	-	ns
$t_r$	Rise Time	$I_D=1A$	-	11	-	ns
$t_{d(off)}$	Turn-off Delay Time	$R_G=3.3\Omega$	-	38	-	ns
$t_f$	Fall Time	$V_{GS}=5V$	-	7	-	ns
$C_{iss}$	Input Capacitance	$V_{GS}=0V$	-	1520	2430	pF
$C_{oss}$	Output Capacitance	$V_{DS}=10V$	-	175	-	pF
$C_{rss}$	Reverse Transfer Capacitance	$f=1.0\text{MHz}$	-	155	-	pF
$R_g$	Gate Resistance	$f=1.0\text{MHz}$	-	1.2	2.4	$\Omega$

**Source-Drain Diode**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{SD}$	Forward On Voltage <sup>2</sup>	$I_S=1.2A, V_{GS}=0V$	-	-	1.2	V
$t_{rr}$	Reverse Recovery Time	$I_S=6A, V_{GS}=0V,$	-	16	-	ns
$Q_{rr}$	Reverse Recovery Charge	$di/dt=100A/\mu s$	-	8	-	nC

**Notes:**

1. Pulse width limited by Max. junction temperature.
2. Pulse test
3. Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board,  $t \leq 10\text{sec}$ ;  $270^{\circ}\text{C}/W$  when mounted on min. copper pad.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

XSEMI DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT

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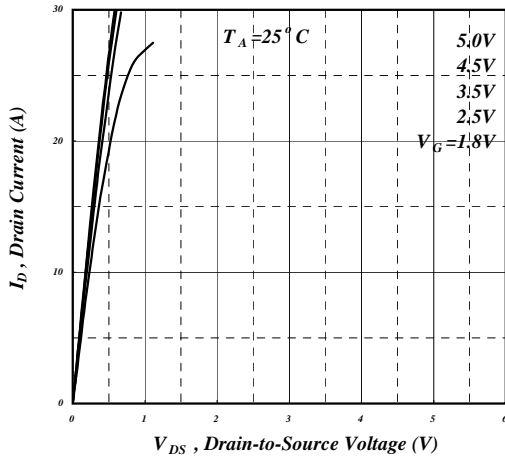


Fig 1. Typical Output Characteristics

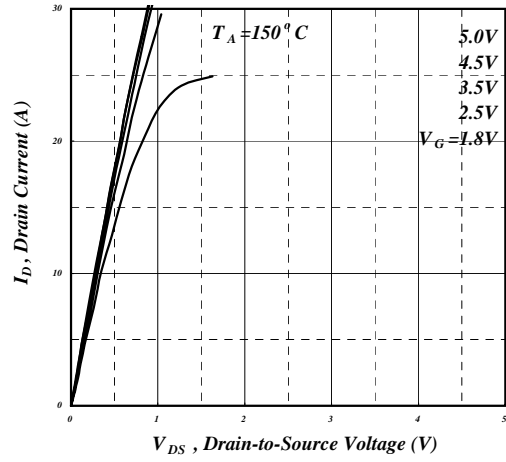


Fig 2. Typical Output Characteristics

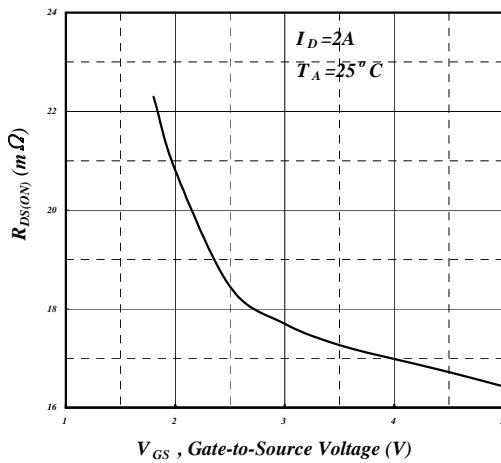


Fig 3. On-Resistance v.s. Gate Voltage

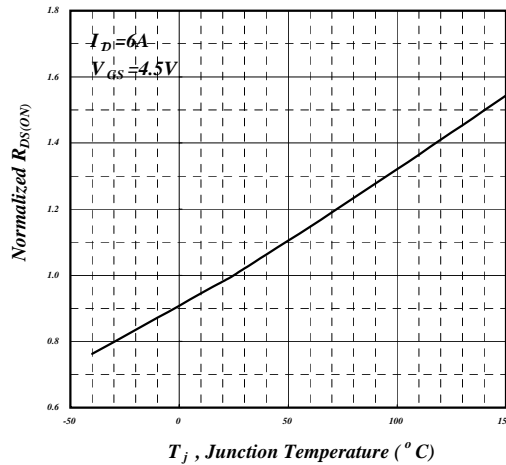


Fig 4. Normalized On-Resistance v.s. Junction Temperature

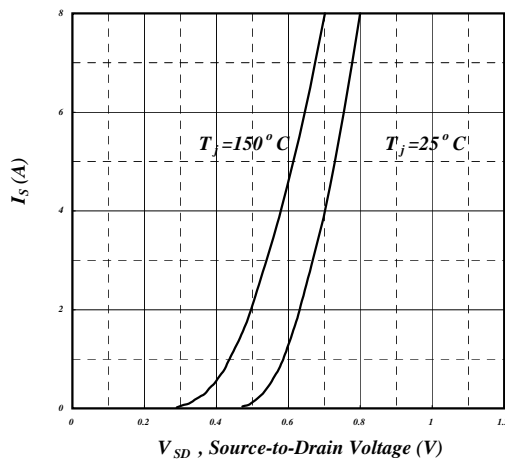


Fig 5. Forward Characteristic of Reverse Diode

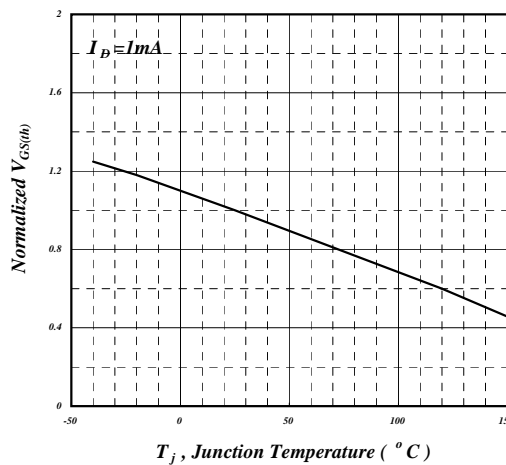


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

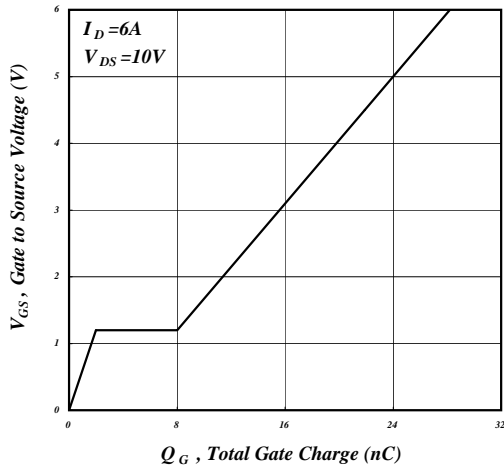


Fig 7. Gate Charge Characteristics

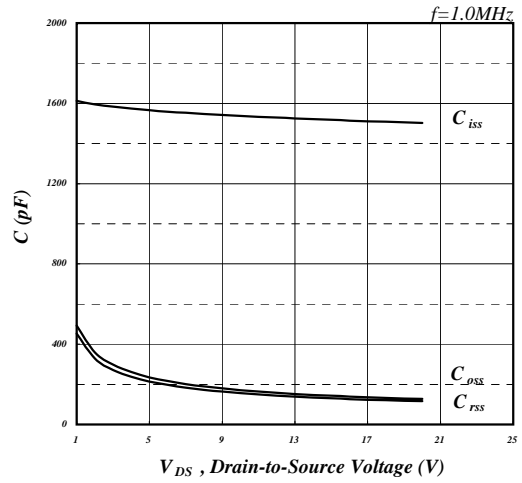


Fig 8. Typical Capacitance Characteristics

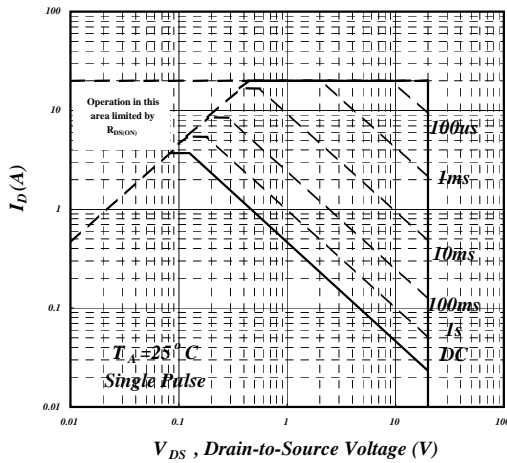


Fig 9. Maximum Safe Operating Area

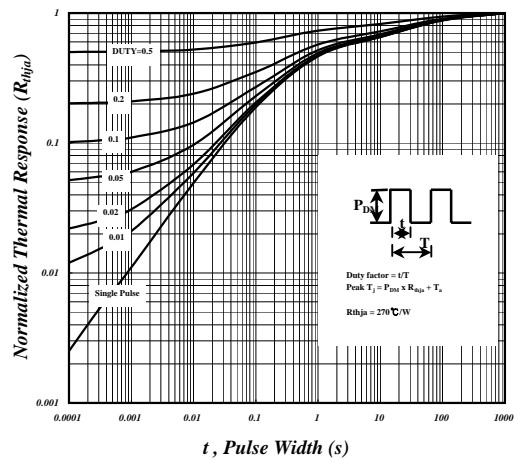


Fig 10. Effective Transient Thermal Impedance

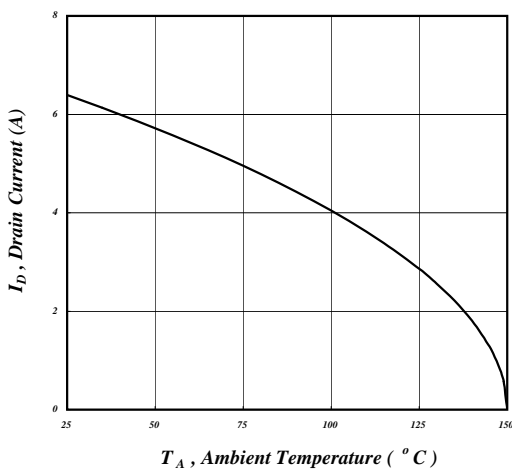


Fig 11. Drain Current v.s. Ambient Temperature

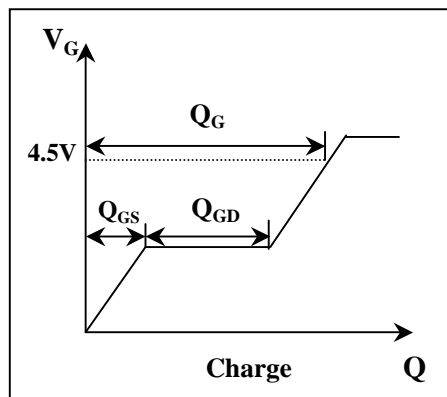


Fig 12. Gate Charge Waveform